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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki, et al.      Art Unit : 2871  
Serial No. : 10/754,702      Examiner : Unknown  
Filed : January 12, 2004  
Title : ACTIVE MATRIX DISPLAY AND FORMING METHOD THEREOF

Commissioner for Patents  
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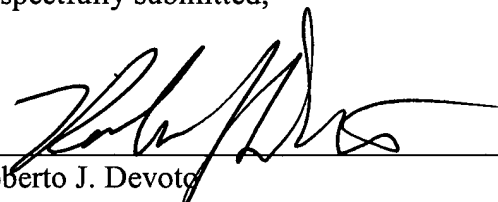
INFORMATION DISCLOSURE STATEMENT

Applicant submits all the references, excluding the U.S. Patents, listed on the attached form PTO-1449.

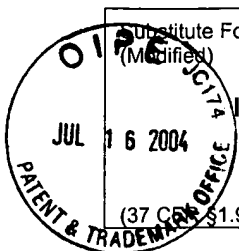
This statement is being filed within three months of the filing date of the application or before receipt of the first office action on the merits. I, the undersigned, hereby certify that each item of information contained in this statement were cited in communications from a foreign patent office in a counterpart foreign application, the communications being dated April 6, 2004 and May 18, 2004. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 7/16/04

  
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-005004	Application No. 10/754,702
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant Shunpei Yamazaki, et al.	
(37 CFR 1.98(b))		Filing Date January 12, 2004	Group Art Unit 2871

### U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	20020195634	12/26/2002	Koyama et al.			
	AB	5,889,291	03/30/1999	Koyama et al.			
	AC	6,441,399	08/27/2002	Koyama et al.			

### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AD	JP-03-126014	5/29/1991	Japan			X	
	AE	JP-04-013116	1/17/1992	Japan			X	
	AF	JP-04-116624	4/17/1992	Japan			X	
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	AP	JP-55-018628	2/8/1980	Japan			X	
	AQ	JP-64-048024	2/22/1989	Japan			X	

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	